

JCG6 Rec'd PCT/PTO 24 MAY 2005

**INFORMATION DISCLOSURE NOTATION**  
*(Use several sheets if necessary)*

Docket Number (Optional)

FIS920020105

Applicant(s)

Doris, et al.

Filing Date

11/25/02

Application Number

107536483

Group Art Unit

To be assigned

2826

**U.S. PATENT DOCUMENTS**

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		3,602,841	8-31-71	McGroddy			
		4,665,415	5-12-87	Esaki, et al.			
		4,853,076	8-1-89	Tsaur, et al.			
		4,855,245	8-8-89	Neppl, et al.			
		4,952,524	8-28-90	Lee, et al.			

**U.S. PATENT APPLICATION PUBLICATIONS**

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		US 2001/0009784 A1	7-26-01	Ma, et al.			
		US 2002/0063292 A1	5-30-02	Armstrong, et al.			
		US 2002/0074598 A1	6-20-02	Doyle, et al.			
		US 2002/0086472	7-4-02	Roberds, et al.			

**FOREIGN PATENT DOCUMENTS**

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
BTL		JP64-76755	03-1989	Japan				

**OTHER DOCUMENTS**
*(Including Author, Title, Date, Pertinent Pages, Etc.)*

BTL		Kern Rim, et al., "Transconductance Enhancement in Deep Submicron Strained-Si n-MOSFETs". International Electron Devices Meeting, 26, 8, 1, IEEE, September 1998.
BTL		Kern Rim, et al., "Characteristics and Device Design of Sub-100 nm Strained Si N- and PMOSFETs." 2002 Symposium on VLSI Technology Digest of Technical Papers, IEEE, pp. 98-99.

EXAMINER / Benjamin Tzu-Hung Liu

DATE CONSIDERED / (09/13/2006)

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BTL		4,958,213	9-18-90	Eklund, et al.			
BTL		5,006,913	4-9-91	Sugahara, et al.			
BTL		5,060,030	10-22-91	Hoke, et al.			
BTL		5,081,513	1-14-92	Jackson, et al.			
BTL		5,108,843	4-28-92	Ohtaka, et al.			

**U.S. PATENT APPLICATION PUBLICATIONS**

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		US 2002/0086497 A1	7-4-02	Kwok			
BTL		US 2002/0090791 A1	7-11-02	Doyle, et al.			
BTL		US 2003/0032261 A1	2-13-03	Yeh, et al.			
BTL		US 2003/0040158 A1	2-27-03	Saltch			

**FOREIGN PATENT DOCUMENTS**

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							YES	NO

**OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, Etc.)

BTL		Gregory Scott, et al., "NMOS Drive Current Reduction Caused by Transistor Layout and Trench Isolation Induced Stress." International Electron Devices Meeting, 34.4.1, IEEE, September 1999.
BTL		F. Ootsuka, et al., "A Highly Dense, High-Performance 130nm Node CMOS Technology for Large Scale System-on-a-Chip Application." International Electron Devices Meeting, 23.5.1, IEEE, April 2000.

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*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		5,134,085	7-28-92	Gilgen, et al.			
BTL		5,310,446	5-10-94	Konishi, et al.			
BTL		5,354,695	10-11-94	Leedy			
BTL		5,371,399	12-6-94	Burroughes, et al.			
BTL		5,391,510	2-21-95	Hsu, et al.			

**U.S. PATENT APPLICATION PUBLICATIONS**

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		US 2003/0057184 A1	3-27-03	Yu, et al.			
BTL		US 2003/0067035 A1	4-10-03	Tews, et al.			

**FOREIGN PATENT DOCUMENTS**

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO

**OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, Etc.)

BTL		Shinya Ito, et al., "Mechanical Stress Effect of Etch-Stop Nitride and Its Impact on Deep Submicron Transistor Design." International Electron Devices Meeting, 10.7.1, IEEE, April 2000.
BTL		A. Shimizu, et al., "Local Mechanical Stress Control (LMC): A New Technique for CMOS Performance Enhancement." International Electron Devices Meeting, IEEE, March 2001.

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**U.S. PATENT DOCUMENTS**

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		5,459,346	10-17-95	Asakawa, et al.			
BTL		5,471,948	12-5-95	Burroughes, et al.			
BTL		5,557,122	9-17-96	Shrivastava, et al.			
BTL		5,561,302	10-1-96	Candelaria			
BTL		5,565,697	10-15-96	Asakawa, et al.			

**U.S. PATENT APPLICATION PUBLICATIONS**

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**OTHER DOCUMENTS** *(Including Author, Title, Date, Pertinent Pages, Etc.)*

BTL		K. Ota, et al., "Novel Locally Strained Channel Technique for High Performance 55nm CMOS." International Electron Devices Meeting, 2.2.1, IEEE, February 2002.
BTL		G. Zhang, et al., "A New 'Mixed-Mode' Reliability Degradation Mechanism in Advanced Si and SiGe Bipolar Transistors." IEEE Transactions on Electron Devices, vol. 49, no. 12, December 2002, pp. 2151-56.

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**U.S. PATENT DOCUMENTS**

*EXAMINER INITIAL	REP	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		5,571,741	11-5-96	Leedy			
BTL		5,592,007	1-7-97	Leedy			
BTL		5,592,018	1-7-97	Leedy			
BTL		5,670,798	9-23-97	Schetzina			
BTL		5,679,965	10-21-97	Schetzina			

**U.S. PATENT APPLICATION PUBLICATIONS**

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**OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, Etc.)

BTL		H.S. Momose, et al., "Temperature Dependence of Emitter-Base Reverse Stress Degradation and Its Mechanism Analyzed by MOS Structures." Paper 6.2, pp. 140-143.
BTL		C.J. Huang, et al., "Temperature Dependence and Post-Stress Recovery of Hot Electron Degradation Effects in Bipolar Transistors." IEEE 1991 Bipolar Circuits and Technology Meeting 7.5, pp. 170-173.

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**U.S. PATENT DOCUMENTS**

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		5,683,934	11-4-97	Candelaria			
BTL		5,840,593	11-24-98	Leedy			
BTL		5,861,651	1-19-99	Brasen, et al.			
BTL		5,880,040	3-9-99	Sun, et al.			
BTL		5,940,716	8-17-99	Jin, et al.			

**U.S. PATENT APPLICATION PUBLICATIONS**

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**OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, Etc.)

BTL		S.R. Sheng, et al., "Degradation and Recovery of SiGe HBTs Following Radiation and Hot-Carrier Stressing." Pp. 14-15.
BTL		Z. Yang, et al., "Avalanche Current Induced Hot Carrier Degradation in 200 GHz SiGe Heterojunction Bipolar Transistors." Pp. 1-5.

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*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		5,940,736	8-17-99	Brady, et al.			
BTL		5,946,559	8-31-99	Leedy			
BTL		5,960,297	9-28-99	Said			
BTL		5,989,978	11-23-99	Peidous			
BTL		6,008,126	12-28-99	Leedy			

**U.S. PATENT APPLICATION PUBLICATIONS**

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**OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, Etc.)

BTL		H. Li, et al., "Design of W-Band VCOs with High Output Power for Potential Application in 77 GHz Automotive Radar Systems." 2003 IEEE GaAs Digest, pp. 263-66.
BTL		H. Wurzer, et al., "Annealing of Degraded npn-Transistors- Mechanisms and Modeling." IEEE Transactions on Electron Devices, vol. 41, no. 4, April 1994, pp. 533-38.

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*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		6,025,280	2-15-00	Brady, et al.			
BTL		6,046,464	4-4-00	Schetzina			
BTL		6,066,545	5-23-00	Doshi, et al.			
BTL		6,090,684	7-18-00	Ishitsuka, et al.			
BTL		6,107,143	8-22-00	Park, et al.			

**U.S. PATENT APPLICATION PUBLICATIONS**

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**OTHER DOCUMENTS** (Including Author, Title, Date, Pertinent Pages, Etc.)

BTL		B. Doyle, et al., "Recovery of Hot-Carrier Damage in Reoxidized Nitrided Oxide MOSFETs." IEEE Electron Device Letters, vol. 13, no. 1, January 1992, pp. 38-40.
BTL		H.S. Momose, et al., "Analysis of the Temperature Dependence of Hot-Carrier-Induced Degradation in Bipolar Transistors for Bi-CMOS." IEEE Transactions on Electron Devices, vol. 41, no. 6, June 1994, pp. 978-987.

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**U.S. PATENT DOCUMENTS**

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		6,117,722	9-12-00	Wuu, et al.			
BTL		6,133,071	10-17-00	Nagai			
BTL		6,165,383	12-26-00	Chou			
BTL		6,221,735	4-24-01	Manley, et al.			
BTL		6,228,694	5-8-01	Doyle, et al.			

**U.S. PATENT APPLICATION PUBLICATIONS**

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**U.S. PATENT DOCUMENTS**

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BTL		6,246,095	6-12-01	Brady, et al.			
BTL		6,255,169	7-3-01	Li, et al.			
BTL		6,261,964	7-17-01	Wu, et al.			
BTL		6,265,317	7-24-01	Chiu, et al.			
BTL		6,274,444	8-14-01	Wang			

**U.S. PATENT APPLICATION PUBLICATIONS**

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BTL		6,281,532	8-28-01	Doyle, et al.			
BTL		6,284,623	9-4-01	Zhang, et al.			
BTL		6,284,626	9-4-01	Kim			
BTL		6,319,794	11-20-01	Akatsu, et al.			
BTL		6,361,885	3-26-02	Chou			

**U.S. PATENT APPLICATION PUBLICATIONS**

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BTL		6,362,082	3-26-02	Doyle, et al.			
BTL		6,368,931	4-9-02	Kuhn, et al.			
BTL		6,403,486	6-11-02	Lou			
BTL		6,403,975	6-11-02	Brunner, et al.			
BTL		6,406,973	6-18-02	Lee			

**U.S. PATENT APPLICATION PUBLICATIONS**

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BTL		6,461,936	10-8-02	von Ebrenewall			
BTL		6,476,462	11-5-02	Shimizu, et al.			
BTL		6,483,171	11-19-02	Forbes, et al.			
BTL		6,493,497	12-10-02	Ramdani, et al.			
BTL		6,498,358	12-24-02	Lach, et al.			

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BTL		6,501,121	12-31-02	Yu, et al.			
BTL		6,506,652	1-14-03	Jan, et al.			
BTL		6,509,618	1-21-03	Jan, et al.			
BTL		6,521,964	2-18-03	Jan, et al.			
BTL		6,531,369	3-11-03	Ozkan, et al.			

**U.S. PATENT APPLICATION PUBLICATIONS**

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BTL		6,531,740	3-11-03	Bosco, et al.			
BTL		6,621,392	9-16-03	Volant, et al.			
BTL		6,635,506	10-21-03	Volant, et al.			

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Group Art Unit

2826

To be assigned

**U.S. PATENT DOCUMENTS**

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
BTL		6,342,410	1-29-02	Yu			
BTL		6,413,802	7-2-02	Hu, et al.			
BTL		6,433,609	8-13-02	Voldman			
BTL		6,458,662	10-1-02	Yu			

**U.S. PATENT APPLICATION PUBLICATIONS**

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE

**FOREIGN PATENT DOCUMENTS**

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO

**OTHER DOCUMENTS**

(Including Author, Title, Date, Pertinent Pages, Etc.)


EXAMINER

/Benjamin Tzu-Hung Liu

DATE CONSIDERED

/ (09/13/2006)

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.